

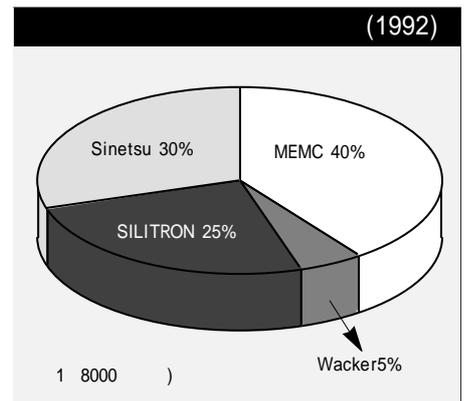
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“ 28% ”

92 1 6300 가 400
 24% 91 17.5% 27% 가 93
 28% 75% MEMC가 40% , Sinetsu
 30%, Wacker 5% 25%
 MEMC(40%), (20%), (40%)
 6", 8" 66MSI
 Nagano OEM
 50% 20%,
 10% MEMC,
 Sinetsu, Waker, 8" Wacker M/S가
 93

(: MSI, 100)				
	1991	1992	1993	1994
	1,782	1,889	2,059	2,306
	2,090	2,215	2,414	2,700

(: 100 , %)				
	1991	1992	1993	1994
	153	154	163	193
	0.7	3.2	3.5	5
	153.7	157.2	166.5	198
	24	27.5	43	59
	130	130	133	144
	154	157.5	176	203
	15.6	17.5	24	28



2053 MSI, 24 1400 60%()
 Poly Silicone 7800 Wacker(24%),
 Hemlock(20%), Asmi(13%)가
 M/S Sinetsu 21%, MEMC(19%), MMC(13%), OTC(12%)
 Koma-tsu, Wacker
 Epi 92 LPE가 3" 8500
 3" 1 8000

Epi Wacker(13%) 300MSI Sinetsu(25%), OTC(17%) MEMC(14%),
 (Polycrystal Silicon)

IC, LSI, VLSI ULSI
 , Amorphous 3 , Amorphous
 가 가

Bipola IC, NMOS, CMOS
 1M 4M DRAM 가 가
 가

Dopants
 (Electron) (Hole)
 Si, Ge GaAs 가
 Si가 가
 FZ(Floating Zone) CZ(Czochralski) MCZ(가 CZ)
 FZ 가 가 CZ

IC Power Device, Bipolar IC, Discrete
 가 FZ 가
 MCZ CCD Power Device 8"
 MCZ

IC 95%
 GaAs, Gap, InP
 MCT(HgCdTe) 6"가 16M DRAM 8"가
 8" 가 8" 가

Epi MOS 가, SRAM, Gate Array, Analog/Digital Devive 가
 Epi Si 가 (B,P,Sb)
 가 Dopant

Device Process
 Device Process
 Damage (Paticle, Scratch)

, 가 .
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& Metal Impurities , 가 Particle, flatness

< 1994/2/1 >